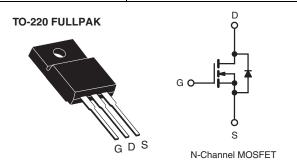


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	800			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	3.0		
Q _g (Max.) (nC)	78			
Q _{gs} (nC)	9.6			
Q _{gd} (nC)	45			
Configuration	Single			



FEATURES

- · Isolated Package
- High Voltage Isolation = 2.5 kV_{RMS} (t = 60 s; f = 60 Hz)



- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 FULLPAK eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. The isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The FULLPAK is mounted to a heatsink using a single clip or by a single screw fixing.

ORDERING INFORMATION	
Package	TO-220 FULLPAK
Local (Db) free	IRFIBE30GPbF
Lead (Pb)-free	SiHFIBE30G-E3
SnPb	IRFIBE30G
	SiHFIBE30G

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	800	V	
Gate-Source Voltage			V_{GS}	± 20	1 v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	I-	2.1		
	VGS at 10 V		ID	1.4	Α	
Pulsed Drain Current ^a			I _{DM}	8.4		
Linear Derating Factor				0.28	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	240	mJ	
Avalanche Current ^a			I _{AR}	2.1	Α	
Repetitive Avalanche Energy ^a			E _{AR}	3.5	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	35	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d		
Mounting Torque	6 22 or l	6-32 or M3 screw		10	lbf ⋅ in	
	6-32 OF M3 SCIEW			1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 102 \, \text{mH}$, $R_G = 25 \, \Omega$, $I_{AS} = 2.1 \, \text{A}$ (see fig. 12).
- c. $I_{SD} \le 4.1$ A, $dI/dt \le 100$ A/ μ s, $V_{DD} \le 600$ V, $T_{J} \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFIBE30G, SiHFIBE30G

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R_{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	3.6	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							ı
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	800	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.90	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	l	V _{DS} = 800 V, V _{GS} = 0 V		-	-	100	μ.Λ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 V	, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.3 A ^b	-	-	3.0	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 1.3 A ^b	1.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V,		-	1300	-	
Output Capacitance	C _{oss}]	$V_{DS} = 25 \text{ V},$		310	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	190	-	pF
Drain to Sink Capacitance	С		f = 1.0 MHz	-	12	-	
Total Gate Charge	Qg		I _D = 4.1 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	78	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	9.6	
Gate-Drain Charge	Q _{gd}		See fig. 6 and 16	-	-	45	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V, } I_D = 4.1 \text{ A,}$ $R_G = 12 \Omega , R_D = 95 \Omega ,$ see fig. 10^b		-	12	-	- ns
Rise Time	t _r			-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2.1	٨
Pulsed Diode Forward Current ^a	I _{SM}			-	-	8.4	- A
Body Diode Voltage	V _{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 2.1 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 4.1 A, dI/dt = 100 A/μs ^b		-	480	720	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	1.8	2.7	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-		on is don	ninated by	L _S and I	_D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

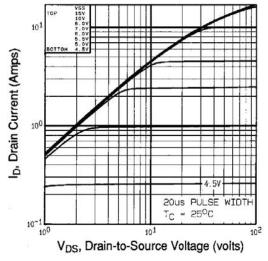


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

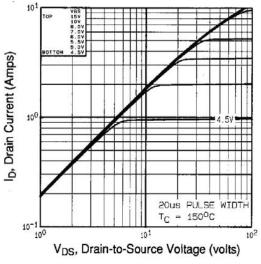


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

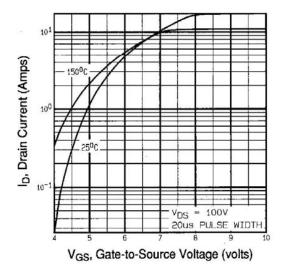


Fig. 3 - Typical Transfer Characteristics

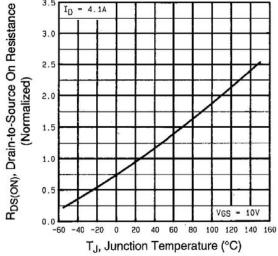


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFIBE30G, SiHFIBE30G

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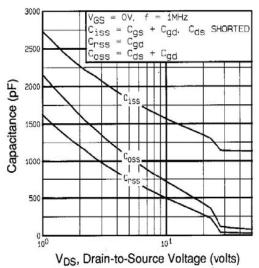
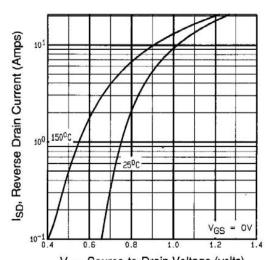


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



V_{SD}, Source-to-Drain Voltage (volts)
Fig. 7 - Typical Source-Drain Diode Forward Voltage

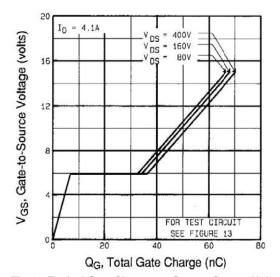


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

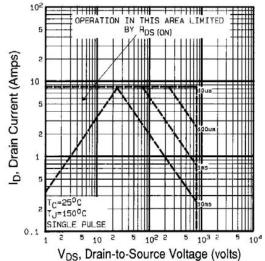


Fig. 8 - Maximum Safe Operating Area



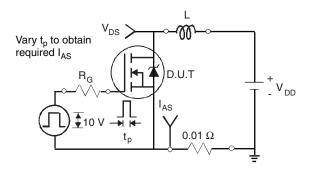


Fig. 9a - Unclamped Inductive Test Circuit

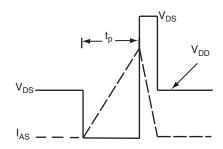


Fig. 9b - Unclamped Inductive Waveforms

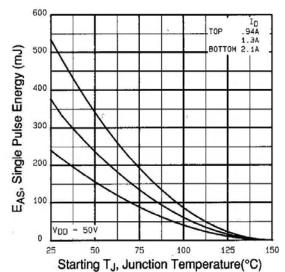


Fig. 9c - Maximum Avalanche Energy vs. Drain Current

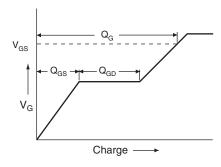


Fig. 10a - Basic Gate Charge Waveform

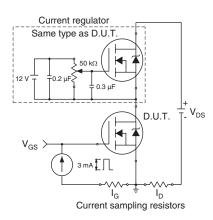
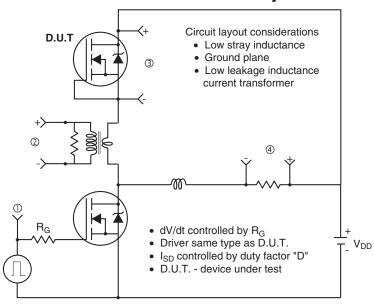


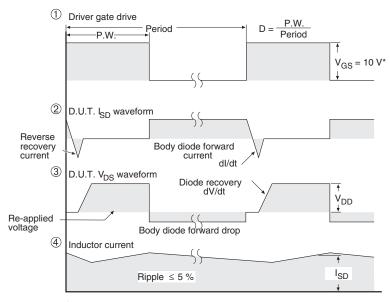
Fig. 10b - Gate Charge Test Circuit

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Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 11 - For N-Channel

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